

WELCOME to the

INTERNATIONAL CONTROL SYSTEMS CONFERENCE

APRIL 26-29, 2026 • COLUMBUS, OHIO

Co-located with TAPPICon

PROGRAM [ver. April 12.]

Monday 27. 13:00 – 15:00	AI / Data Analytics [GCCC – Room A122/123] Seyhan Nuyan, Retired (formerly with Valmet) & Mariana Sandin, SEEQ
13:00 – 13:30	Agentic AI's Impact on Operating Models Michael Vasicek, Kyndryl
13:30 – 14:00	Encoding the SME: AI for Accelerated Learning in Complex Operations Philip Pierce, SEEQ
14:00 – 14:30	Enhancing Mill Operations: Automation and Analytics within the PDCA Framework Matti Hakkinen, Trimble
14:30 – 15:00	AI in the Mill: From Gut Feel to Evidence Mariana Sandin, SEEQ
Monday 27. 16:00 – 17:30	Mill Automation – Dewatering and Moisture Management [GCCC – Room A120/121] Shih-Chin Chen, Retired (formerly with ABB, Inc.) & Rick Wasson, Irving Paper & Melanie Touns, Jacobs
16:00 – 16:30	Closed-Loop Vacuum Control in Papermaking: A Data-Driven Approach to Wet End Optimization Luca Canali, S.A. & Giuseppe Cristini S.p.A.
16:30 – 17:00	Airflow-based Vacuum Control for Optimizing Felt Dewatering Petteri Halme, Valmet Technologies, Inc.
17:00 – 17:30	Enhanced Paper Machine Controls and Process Optimization with LWIR Cameras Slawek Frackowiak, Industrial Video Solutions & Mickey Held, Honeywell
Tuesday 28. 08:00 – 09:30	Pulp Mill Measurement and Control (CSC) [GCCC – Room A122/123] Antonio Suarez, Smurfit WestRock
08:00 – 08:30	Transitions for Pulp Mills Ramesh Satini, ABB Pte Ltd.
08:30 – 09:00	Kraft Lab Liquor Testing Advancements Shawn Russel, FITNIR
09:00 – 09:30	Control of Continuous Digester Kappa Number Using Generalized Model Predictive Control Wesley Gilbert, FPIInnovations
Tuesday 28. 10:00 – 11:30	Measurement Correlations [GCCC – Room A122/123] Lu Athnos, ABB Inc.
10:00 – 10:30	Standardized Dynamic Correlation Practices for Online Sensors Lu Athnos, ABB Inc.
10:30 – 11:00	Caliper Dynamic Correlation – Single Point Method (TIP 1101-10) Mike Butynski, ABB
11:00 – 11:30	Fresh Look at Online-to-Offline Measurement Correlation from a Soft Sensor Perspective Shih-Chin Chen, Retired (formerly with ABB, Inc.)
Tuesday 28. 13:30 – 15:00	Process Control General [GCCC – Room A122/123] Kerry Figiel, OnCareDA
13:30 – 14:00	Increasing Stability with Adaptive Parabolic Algorithm Control Douglas McCallum, McCallum Value Partners

14:00 – 14:30	Beyond Retuning: A Disciplined and Lightweight Program for Sustained Control Loop Health Ian Journeaux, Envoy Development, LLC
14:30 – 15:00	OT Networks And Cybersecurity In Plain Language Amanda Sans, Andritz
Tuesday 28. 16:00 – 17:30	Paper Machine Measurement and Control [GCCC – Room A122/123] Michael Forbes, Honeywell
16:00 – 16:30	Cell Configurations in the ANOVA Interaction Model to Identify Two-Dimensional Patterns in Reel Dat Kerry Figiel, OnCareDA
16:30 – 17:00	Towards Process Excellence: Advanced Optimization of Grade Change Operations in Paper Manufacturing Abhay Anand, ABB Limited
17:00 – 17:30	Paper Color Control: Adaptive Modeling and Predictive Strategies for Optimality and Robustness Calvin Fu, Valmet & Seyhan Nuyan, Retired (formerly Valmet)
Wednesd 29. 10:00 – 12:00	Operator Training & Interface Experience [GCCC – Room A110/111] Katarina Bodor, ABB & Mariana Sandin, Seeg
10:00 – 10:30	Preventing Console Overload David Strobhar, Beville Engineering Inc.
10:30 – 11:00	The Control-Room Co-Pilot: Deploying an AI Assistant That Explains, Watches, and Suggests—Without T Gordon Jones, Envoy Development, LLC
11:00 – 11:30	When Realism Meets ROI: Selecting the Right Fidelity for an Operator Training System Drew Habel, Jedson Engineering
11:30 – 12:00	Grade Change Performance Assessment Through Digital, Persona-Centric Dashboards Maya Manish, ABB Inc.
Wednesd 29. 13:00 – 15:00	Cybersecurity, Safety, and Machine Vision Applications [GCCC – Room A112/113] Brian Mock, Event Capture Systems Inc.
13:00 – 13:30	Old Machines, New Threats: Can Cyber Hygiene Modernize Paper Mill Security? Sourav Kunal, ABB Inc.
13:30 – 14:00	Bridging Safety and Process Control: AI Enabled Real-Time Pinch Zone Hazard Mitigation Matthew Goethel, Detect Technologies USA Inc. & Lorell Carter-Walker, International Paper
14:00 – 14:30	AI-Driven Computer Vision Framework for Compositional Classification and Quality Assessment of Reco Mariangeles Scalas, North Carolina State University
14:30 – 15:00	Improved Quality Inspection for Food and Liquid Packaging Board Using 3D and UV Detection Alex Poltorak, Procemex, Inc.



If you are reading this on paper, this is the link to the on-line page for this document.
[<https://www.handix.se/cs-2026>]



Link to the TappiCon on-line conference registration page.
[<https://events.tappi.org/event/tappicon/regProcessStep1>]



For info about the conference, the venue and Columbus, Ohio,
[<https://events.tappi.org/event/tappicon/control-systems-conference>]

International Program Committee

The final scientific content, invited lectures, panels, and sessions for the conference has been developed with the assistance of the International Program Committee consisting of professionals from North America, Europe and Asia.

The organizers

include representatives from the leading technical associations within the North American and Nordic pulp and paper industries, namely PAPTAC, PI, SPCI, and TAPPI.

